



PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of  
Abdurrahman Sezginer et al.  
Application No.: 10/613,378  
Filed: July 3, 2003  
For: OVERLAY METROLOGY METHOD  
AND APPARATUS USING MORE  
THAN ONE GRATING PER  
MEASUREMENT DIRECTION

Confirmation No.: 7200

Group Art Unit: Unknown

Examiner: Unknown

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**(37 CFR 1.8(a))**

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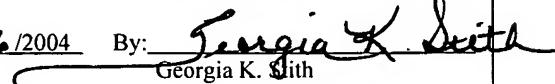
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Dated: 06/16/2004

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